Tao-Ming Chen

List of Publications by Year
in descending order

2 papers	**29** citations	2682572 **2** h-index	2917675 **2** g-index
2 all docs	**2** docs citations	**2** times ranked	**6** citing authors

#	Article	IF	Citations
1	Applying Data Augmentation and Mask R-CNN-Based Instance Segmentation Method for Mixed-Type Wafer Maps Defect Patterns Classification. IEEE Transactions on Semiconductor Manufacturing, 2021, 34, 455-463.	1.7	23
2	Integrating content-based image retrieval and deep learning to improve wafer bin map defect patterns classification. Journal of Industrial and Production Engineering, 2022, 39, 614-628.	3.1	6